## LICATION

OIPE	•	PATENT Sheet 1	APPLICATION of 1	
SEP 0 8 2003 0 FORM PTO-1449	ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION	NO
	200312110-1	10/621,484	] :	
TRANFUL APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT	······································	<u> </u>	
	Stan E. LEIGH, t al.			
	FILING DATE	GROUP		
(Use several sheets if necessary)	07/16/03			
REFERENCE DESIGNATION U.S. PATI	ENT DOCUMENTS			

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
1A				,
1B				
1C				
1 D				
1 E				
1F				
1G				
1H				
11				
1J				
1.K				

## **FOREIGN PATENT DOCUMENTS**

	1	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
}	1N					
	10					
	1P					$\checkmark$

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

.V.	10	H. CERIC, et al.; "ELECTROMIGRATION INDUCED EVOLUTION OF VOIDS IN CURRENT CROWDING AREAS OF INTERCONNECTS"; 2002 IEEE; Proceedings of 9th IPFA 2002, Singapore; Pages140-144.		
	1R			
	15			
EXAMIN		A. Vale -	DATE CONSIDERED	11/16/04